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FORM	1 PTO-1	1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARKS FROM P107318-09007						09/355,946		
		T 05	DEFEDENCE		APPLICANT				EXAMINER		
LIST OF REFERENCES CITED BY APPLICANT NAKAMURA et al.											
		(Use several sheets if necessary)			DEC 0 5 2000 FILING DATE AUGUST 16,			1999 173 4			
U.S. PATENT DOCLUMENTS											
*EXAMINER INITIAL			DOCUMENT NO.	DATE		NAME		CLASS	SUB- CLAS		LING ATE
√	76	> AA	3,201,302	08/17/65	WILLIAMS et al.						
		AB	3,188,258	06/08/65	YOUNG			CH:			
		AC	3,442,737	05/06/69	REED et al.			TICH: OLCGY	目前		
		AD	4,871,499	10/03/89	AUDOUX et al.			1 _			
	<u> </u>	AE	5,503,923	04/02/96	GOTO et al.			T.XTER		1	
• •	\downarrow	AF	4,872,930	10/10/89	KAJIKAWA et al.			FR			
FOREIGN PATENT DOCUMENTS											
			DOCUMENT NO.	DATE		COUNTRY		CLASS	SUB- CLASS	TRANS YES	SLATION NO
7	76	AG	1,118,597	07/03/68		Great Britain				×/	
		АН	0365112A2	04/25/90		Europe				X /	
		AI	6-340849	12/13/94		Japan AGSTRAT				X	/
		AJ	EP0737731A2	10/16/96		Europe			$\overline{}$	x /	
	<u> </u>		7-214734	08/15/95	Japan RBJTRAKT				X	/	
		AL		······································							
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)											
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6 march 2001

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Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.